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PATENT NUMBER and
ISSUE DATE

U.S. UTILITY Patent Application

APPL NUM	FILING DATE	CLASS	SUBCLASS	GAU	EXAMINER
10072805	02/08/2002	250	7	2881	

****APPLICANTS:** Kazumori Hiroyoshi;

****CONTINUING DATA VERIFIED:**

**** FOREIGN APPLICATIONS VERIFIED:**

PG-PUB	DO NOT PUBLISH <input type="checkbox"/>	RESCIND <input type="checkbox"/>
Foreign priority claimed <input type="checkbox"/> yes <input checked="" type="checkbox"/> no		ATTORNEY DOCKET NO
35 USC 119 conditions met <input type="checkbox"/> yes <input checked="" type="checkbox"/> no		116-020069
Verified and Acknowledged Examiners's initials		
TITLE : Scanning electron microscope and method of detecting electrons therein		

U.S. DEPT. OF COMM./PAT. & TM.-PTO-436L (Rev. 12-94)

NOTICE OF ALLOWANCE MAILED		CLAIMS ALLOWED		
		Total Claims		Print Claim for O.G.
Assistant Examiner		DRAWING		
		Sheets Drwg.	Figs. Drwg.	Print Fig.
Amount Due		Application Examiner		
Date Paid				
<input type="checkbox"/> TERMINAL DISCLAIMER		PREPARED FOR ISSUE		
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